

FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary) <div style="border: 1px solid black; border-radius: 50%; padding: 5px; display: inline-block;"> JUL 09 2004 PATENT & TRADEMARK OFFICE </div>				ATTY DOCKET NO. 03500.017455		APPLICATION NO. 107730,033	
				APPLICANT Toshihiko Ouchi			
				FILING DATE December 9, 2003		GROUP 2874	

U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
<i>Jh</i>	5,835,646	11/10/98	Yoshimura et al.	385	14		
<i>Jh</i>	6,097,472	08/01/00	Tanaka et al.	355	47		
<i>Jh</i>	6,343,171 B1	01/29/02	Yoshimura et al.	385	50		
<i>Jh</i>	6,516,104 B1	02/04/03	Furuyama et al.	385	14		
<i>Jh</i>	5,712,504	01/27/98	Yano et al.	257	452		
<i>Jh</i>	6,505,409 B2	01/14/03	Toda et al.	33	366.24		
<i>Jh</i>	6,509,645 B2	01/21/03	Tatsumi et al.	257	738		

FOREIGN PATENT DOCUMENTS							
DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT		
<i>Jh</i> JP 9-270751	10/14/97	Japan			Translation		
<i>Jh</i> JP 59-75656	04/28/84	Japan			Translation		
<i>Jh</i> JP 8-220357	8/30/96	Japan			Abstract		
<i>Jh</i> JP 9-96746	04/8/97	Japan			Abstract		
<i>Jh</i> JP 10-294254	11/04/98	Japan			Abstract		

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)	
<i>Jh</i>	Steven C. Binari et al., "GaN FETs for Microwave and High-temperature Applications," 41(2) Solid-State Electronics 177-80 (1997).
<i>Jh</i>	Seikoh Yoshida et al., "High-temperature Reliability of GaN Metal Semiconductor Field-Effect Transistor and Bipolar Junction Transistor," 85(11) J. Appl. Phys. 7931-34 (June 1999).

EXAMINER <i>Jubian Koz</i>	DATE CONSIDERED <i>9/2/04</i>
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>Jh</i>		6,563,137 B2	05/13/03	Uchida	257	84	
<i>Jh</i>		6,499,899 B1	12/31/02	Shirakawa et al.	385	88	
<i>Jh</i>		6,611,000 B2	08/26/03	Tamura et al.	257	80	03/12/02
<i>Jh</i>		6,366,375 B1	04/02/02	Sakai et al.	359	115	
<i>Jh</i>		5,191,219	03/02/93	Linke	250	551	
<i>Jh</i>		2004/0061224 A2	04/01/04	Tatsumi et al.	257	737	09/27/02
<i>Jh</i>		2003/0020164 A1	01/30/03	Tatsumi et al.	257	737	
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		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
<i>Jh</i>	JP	11-54406	02/26/99	Japan			Abstract
<i>Jh</i>	JP	11-72750	03/16/99	Japan			Translation
<i>Jh</i>	JP	11-111609	04/23/99	Japan			Abstract
<i>Jh</i>	JP	11-196069	07/21/99	Japan			Abstract
<i>Jh</i>	JP	2000-31189	01/28/00	Japan			Abstract
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER <i>Jubran K...</i>				DATE CONSIDERED <i>9/2/04</i>			

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U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
<i>Jh</i>	2002/0167013 A1	11/14/02	Iwasaki et al.	257	79		
	2002/0132462 A1	09/19/02	Tatsumi et al.	438	613		

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JP 2000-235127	08/29/00	Japan			Abstract		
JP 2000-337872	12/08/00	Japan			Abstract		
JP 2001-284635	10/12/01	Japan			Abstract		
JP 61-28240	02/07/86	Japan			Abstract		

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)		

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